Freeform Search

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Term:	L7 and (histogram and (parent or child))				
	Documents in <u>Display Format</u> : - Starting with Number 1				
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DB=PC	GPB, USPT; PLUR=YES; OP=ADJ		
<u>L8</u>	L7 and (histogram and (parent or child))	5	<u>L8</u>
<u>L7</u>	('6247016' '6138115' '6055539' '5799311' '5787274')!.PN.	5	<u>L7</u>
<u>L6</u>	histogram near3 (parent or child)	. 19	<u>L6</u>
<u>L5</u>	L4 and (bucket near3 boundary)	2	<u>L5</u>
<u>L4</u>	6507840.pn. or 5870752.pn. or 6772142.pn.	3	<u>L4</u>
<u>L3</u>	L2 and L1	6	<u>L3</u>
<u>L2</u>	resistance near3 temperature near3 inverse	84	<u>L2</u>
Ll	bolometer	1462	L1

END OF SEARCH HISTORY

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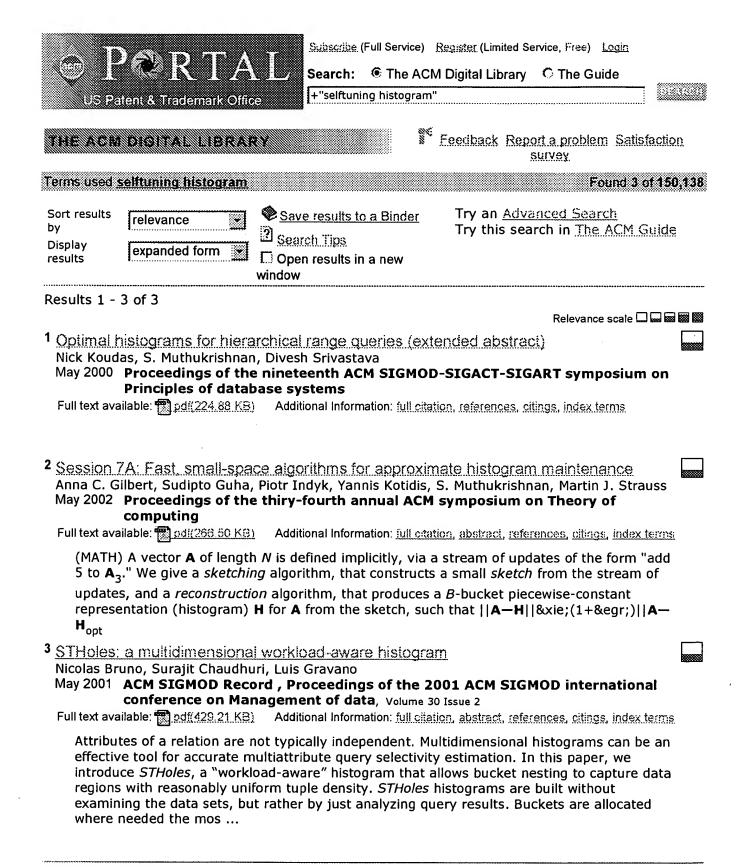


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